

1. Record Nr.	UNINA9910785711603321
Titolo	Electron microscopy XIV : selected, peer reviewed papers from the XIV International Conference on Electron Microscopy (EM2011), June 26-30, 2011, Wisla, Poland // edited by Danuta Stroz and Krystian Prusik
Pubbl/distr/stampa	Durnten-Zurich, Switzerland ; ; Enfield, NH, USA : , : TTP, , [2012] ©2012
ISBN	3-03813-699-9
Descrizione fisica	1 online resource (352 p.)
Collana	Solid state phenomena, , 1012-0394 ; ; volumes 186
Altri autori (Persone)	StrozDanuta PrusikKrystian
Disciplina	502.825
Soggetti	Electron microscopy
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references and indexes.
Nota di contenuto	Electron Microscopy XIV; Preface and Conference Photo; Table of Contents; Methods of Electron Crystallography as Tools for Materials Analysis; Characterization of Grain Boundary Geometry in the TEM, Exemplified in Si Thin Films; Orientation and Phase Mapping in TEM Microscopy (EBSD-TEM Like): Applications to Materials Science; The Art and Application of Large Angle Convergent Beam Electron Diffraction; Cathodoluminescence and Electroluminescence of Semiconductor Structures in SEM; Secondary Electron Detector with the Unipotential Lens Structure for Variable Pressure/Environmental SEM A Quantitative Analytical Method for the Identification and Characterization of Mineralized Nanoparticles in Food Supplements Physical and Chemical Studies of Bacterial Bioaerosols at Wastewater Treatment Plant Using Scanning Electron Mikroskopy and X-Ray Photoelectron Spectroscopy; 3D Imaging and Metrology of Yttria Dispersoids in INCOLOY MA956 by Electron Tomography; 3D Imaging of Strengthening Particles in Cr-V-Mo (13HMF) Steel Using FIB/SEM Tomography; Three-Dimensional Visualization and Metrology of Nanoparticles in Inconel 718 by Electron Tomography Martensitic Transformation in Ti50Ni25Cu25 Shape Memory Alloy Studied by EBSD Investigations of Fine Grained Metallic Materials by Means of Orientation Maps in Transmission Electron Microscope; Phase

Identification in Nickel-Based Superalloys Using EBSD/SEM and Electron  
 Diffraction in STEM; High Resolution EBSD/SEM Analysis of PLZT  
 Ferroelectric Crystals in Low Vacuum Conditions - A few Practical  
 Remarks; Study of Silicon Nanoparticles Formation in Silicon Nitride;  
 Structural and Chemical Characterization of Al(Ga)N/GaN Quantum Well  
 Structures Grown by Plasma Assisted Molecular Beam Epitaxy  
 Wurtzite-to Amorphous-to Cubic Phase Transition of GaN1-XAsx  
 Alloys with Increasing as Content Study of Oxides Formed in HfO2/Si  
 Structure for High-k Dielectric Applications; Ni-Based Ohmic Contacts  
 to Silicon Carbide Examined by Electron Microscopy; Crystallization and  
 Microstructure of Co<sub>0.75</sub>Ni<sub>0.25</sub>Si<sub>2</sub> Solid Solution; Nanotexture Studies  
 of NiTi Shape Memory Alloy after Severe Plastic Deformation with the  
 Use of TEM; SEM EBSD and TEM Structure Studies of -Brass after  
 Severe Plastic Deformation Using Equal Channel Rolling Followed by  
 Groove Pressing  
 Crystallographic Aspects of Deformation and Recrystallization in ECAP-  
 Processed AA3104 Aluminium Alloy Microstructure of the Ni-W Solid  
 Solution Prepared by Levitation and after High Pressure Torsion Severe  
 Plastic Deformation; Near Grain Boundary Behavior of Aluminum  
 Bicrystals Deformed in Plane Strain Conditions; Microstructure and  
 Texture Evolutions in AA1200 Aluminum Alloy Deformed by  
 Accumulative Roll Bonding Method; Gradient Microstructure of  
 FeCr<sub>30</sub>Co<sub>8</sub> Hard Magnetic Alloy Subjected to Plastic Deformation by  
 Tension Combined with Torsion at 700 and 720°C  
 Effect of Rapid Solidification on the Structure and Mechanical Properties  
 of AZ91 Magnesium Alloy

#### Sommario/riassunto

These are the proceedings of the XIV International Conference on  
 Electron Microscopy (EM2011) held in Wisla, Poland from the 26 to 30th  
 June 2011. The goal of the conference was to provide a forum where  
 researchers from many different countries could exchange their latest  
 advances in the field of structural studies, regarding the use of electron  
 microscopic techniques as applied to various materials. Plenary and  
 invited lectures offered overviews of exciting new developments which  
 highlighted the applications of new electron microscopic techniques in  
 physics, chemistry, materials science and i